

<b>Notice of References Cited</b>	Application/Control No. 09/837,887	Applicant(s)/Patent Under Reexamination VOORAKARANAM ET AL.	
	Examiner Hal D Wachsman	Art Unit 2857	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,625,785	09-2003	Chatterjee et al.	716/4
	B	US-5,341,315	08-1994	Niwa et al.	714/738
	C	US-4,991,176	02-1991	Dahbura et al.	714/738
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N					
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	Q					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Balivada et al., "Analog Testing with Time Response Parameters", 1996, IEEE Design & Test of Computers, pages 18-25.
	V	Voorakaranam et al., "Low-Cost Signature Testing of RF Circuits", no date on reference, pages 2-11.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.